

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/773,629	KRISHNAN ET AL.
Examiner	Art Unit	
	JOHN J. LEE	2618

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
455	522,69	9/26/2008	J.L.
455	126,70	9/26/2008	J.L.
455	67.11-13	9/26/2008	J.L.
Interference and Inventor search		9/26/2008	J.L.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**